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## **APPENDIX 3: Photographs of test setup**

### **Conducted emission**

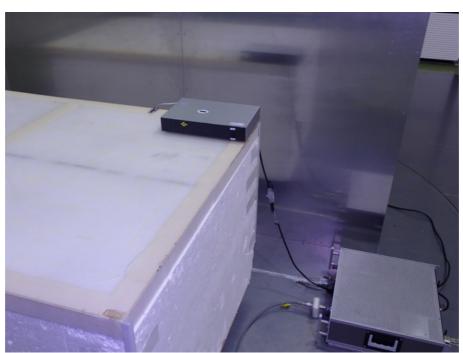


Photo 1

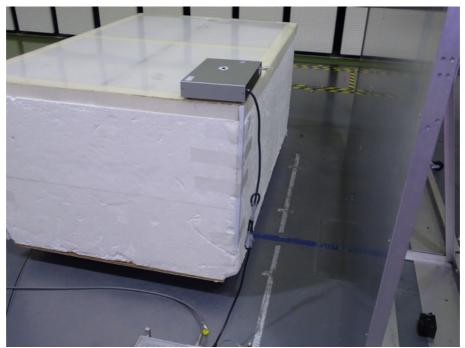


Photo 2

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## **Radiated emission**



Photo 1

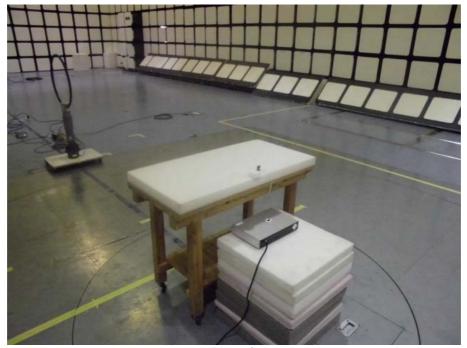


Photo 2

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### **Worst Case Position**

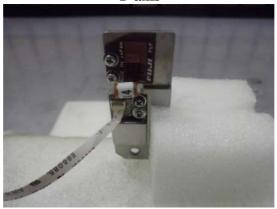
Below 30MHz Y-axis

Above 30MHz Horizontal:X-axis / Vertical:X-axis

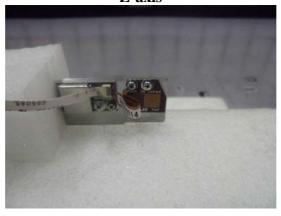
## X-axis



Y-axis



**Z**-axis

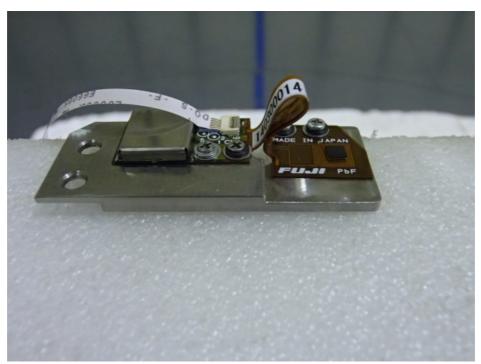


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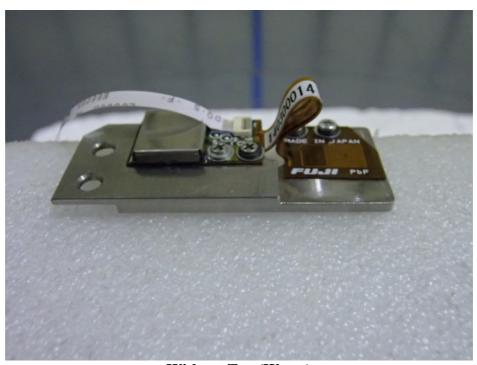
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## With/Without Tag



With Tag



Without Tag (Worst)

## **End of Report**

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